

**AUTOMATIC EXCHANGE OF DEGRADERS**  
**IN ACCELERATED TESTING OF COMPUTER CHIPS**

**Abstract of the Disclosure**

Issues that are addressed in accordance with at least one presently preferred  
5 embodiment of the present invention, are: improvements upon the time it takes to  
physically swap degraders (done previously by hand); the safety involved in doing so,  
since the degraders become highly radioactive; possible improved energy resolution and  
beam stability if the accelerator can be left running continuously; and in-situ monitoring  
of beam current, beam position and stability. Particularly contemplated are methods and  
10 arrangements for changing degraders automatically, not manually, and in a safe manner.